

SHEET 10/519406

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 263098US2X PCT	SERIAL NO. 10/519,406 New U.S. PCT Application Based on PCT/FR03/02225		
		LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Lea DI CIOCCIO, et al.			
		FILING DATE Herewith 01/05/2005	GROUP 2813				
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
(C)	AA	6 150 239	11/21/00	TONG, Qin-Metal Goesele et al	438	458	
	AB						
	AC						
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
(C)	AO	02 37556	05/10/02	WO(with English abstract)			NO
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
(C)	AV	HUGONNARD-BRUYERE E ET AL: "Electrical and physical behavior of SiC layers on insulator (SiCOI)" INTERNATIONAL CONFERENCE ON SILICON CARBIDE AND RELATED MATERIALS, ICSRM'99, vol. 338-342, pt. 1, pages 715-718, October 1999.					
(C)	AW	HUGONNARD-BRUYERE E ET AL: "Defect Studies in Epitaxial SiC-6H layers on Insulator (SiCOI)" MICROELECTRONIC ENGINEERING, vol. 48, no. 1-4, pages 277-280, September 1999.					
(C)	AX	HUGONNARD-BRUYERE E ET AL: "Deep level defects in Implanted 6H-SiC epilayers and in silicon carbide on insulator structures" MATERIAL SCIENCE AND ENGINEERING B, vol. 61-62, pages 382-388, July 30, 1999.					
(C)	AY	GREGORY R B ET AL: "The effects of damage on hydrogen-implant-induced thin-film separation from bulk silicon carbide" WIDE-BANDGAP SEMICONDUCTORS FOR HIGH-POWER, HIGH-FREQUENCY AND HIGH-TEMPERATURE APPLICATIONS-1999. SYMPOSIUM, WIDE-BANDGAP SEMICONDUCTORS FOR HIGH-POWER, HIGH-FREQUENCY AND HIGH-TEMPERATURE APPLICATIONS -1999, vol. 572, pages 33-38, 1999.					
(C)	AZ	BINARI S C ET AL: "H, He, and N implant isolation of n-type GaN" JOURNAL OF APPLIED PHYSICS, vol. 78, no. 5, September 1, 1995.					
				<input type="checkbox"/> Additional References sheet(s) attached			
Examiner <i>Colleen Edgoff</i>				Date Considered 29 Jan 2007			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							